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	SPEC No.   E L O 8 7 1 0 7 ISSUE: Jul. 17. 1996
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SPE	CIFICATIONS
Product Type	2 5 6 k S R A M
LH !	5 2 2 5 6 C H N - 8 5 L L
Model No.	( LH525C2N )
	ons contains <u>16</u> pages including the cover and appendix. bjections, please contact us before issuing purchasing orde
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    - · Office electronics
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    - · Machine tools
    - · Audiovisual equipment
    - · Home appliances
    - · Communication equipment other than for trunk lines
  - (2) Those contemplating using the products covered herein for the following equipment which demands high reliability, should first contact a sales representative of the company and then accept responsibility for incorporating into the design fail-sale operation, redundancy, and other appropriate measures for ensuring reliability and safety of the equipment and the overall system.
    - · Control and safety devices for airplanes, trains, automobiles, and other transportation equipment
    - · Mainframe computers
    - · Traffic control systems
    - · Gas leak detectors and automatic cutoff devices
    - · Rescue and security equipment
    - · Other safety devices and safety equipment, etc.
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    - · Aerospace equipment
    - · Communications equipment for trunk lines
    - · Control equipment for the nuclear power industry
    - · Medical equipment related to life support, etc.
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- Please direct all queries regarding the products covered herein to a sales representative of the company.

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#### 1. Decription

The LH52256CHN-85LL is a static RAM organized as 32, 768 $\times$ 8 bit with provides low-power standby mode.

It is fabricated using silicon-gate CMOS process technology.

#### Features

 OAccess Time
 . . . .
 8 5 n s (Max.)

 Operating current
 . . . .
 4 0 m A (Max.)

 1 0 m A (Max. t RC, t wc = 1 μ s)

Ostandby current  $\cdots$  40  $\mu$  A (Max. )

Obata retention current  $\cdots$  1.0  $\mu$  A (Max.  $V_{CCDR} = 3 \text{ V}, Ta = 25 \text{ C}$ )

Owide operating voltage range .... 4.5 V to 5.5 V

Operating temperature  $\cdots -4.0 \, ^{\circ}$  to  $+8.5 \, ^{\circ}$ 

OFully static operation

OThree-state output

ONot designed or rated as radiation hardened

 $\bigcirc$  2 8 pin SOP ( SOP 28-P-450 ) plastic package

ON-type bulk silicon

## 2. Pin Configuration

A 14		10	-	28		Vcc
A 12		2		27		WE
A 7		3		26		A 13
A 6		4		25		A 8
A 5		5		24		А 9
A 4		6		23		A 11-
Аз	$\Box$	7		22		ΟE
A 2		8		21		<u>A 10</u>
Аı		9		20		CE
Αo		10		19		I/O 8
I/O 1	$\Box$	11		18		I/O 7
I/O 2	$\Box$	12		17		I/O 6
I/O 3		13		16		I/O 5
GND		14		15		I/O 4
					ا	

(Top View)

Pin Name	Function
A o to A 14	Address inputs
CE	Chip enable
WE	Write enable
ŌE	Output enable
I /O 1 to I /O 8	Data inputs/outputs
Vcc	Power supply
GND	Ground

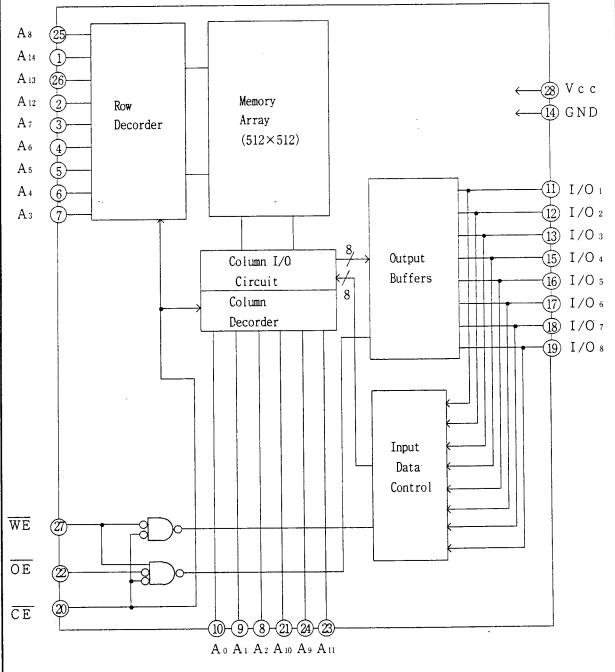


### 3. Truth Table

CE	WE	ΘĒ	Mode	I /O 1 to I /O 8	Supply current
Н	*	*	Standby	High impedance	Standby (Ism)
L	Н	L	Read	Data output	Active (Icc)
L	Н	H	Output disable	High impedance	Active (Icc)
L	L	*	Write	Data Input	Active (Icc)

(\*=Don't Care, L=Low, H=High)





#### 5. Absolute Maximum Ratings

Parameter	Symbol	Ratings	Unit
Supply voltage (*1)	Vcc	-0.5 to $+7.0$	V
Input voltage (*1)	VIN	-0.5 (*2) to Vcc+0.5	V
Operating temperature	Торг	-40 to +85	r
Storage temperature	Tstg	-65 to +150	r

Note) \*1. The maximum applicable voltage on any pin with respect to GND.

\*2. Undershoot of -3.0V is allowed width of pluse bellow 50ns.

### 6. Recommended DC Operating Conditions

$$(Ta = -40 \% to +85)$$

Parameter	Symbol	Min.	Typ.	Max.	Unit
Supply voltage	Vcc	4.5	5.0	5.5	V
Input voltage	VIH	2.2		Vcc+0.5	V
	VIL	-0.5 (*3)		0.8	V

Note) \*3. Undershoot of -3.0V is allowed width of pluse below 50ns.

#### 7. DC Electrical Characteristics

$$(Ta = -4.0 \, \text{°C} \text{ to } + 8.5, \text{Vcc} = 4.5 \, \text{V} \text{ to } 5.5 \, \text{V})$$

		(la=-40C to	+ 8 5, Vcc	4.5 V	to 5.	5 V)
Parameter	Symbol	Conditions	Min.	Typ. (*4)	Max.	Unit
Input leakage	ILI	V <sub>IN</sub> =OV to Vcc				
current			-1.0		1.0	μΑ
Output leakage	ILO	CE =ViH or OE =ViH				
current		V <sub>1/0</sub> =0V to Vcc	-1.0		1.0	μΑ
Operating	Icc	Minimum cycle				
supply		$V_{IN} = V_{IL}$ or $V_{IH}$ , $I_{I/0} = OmA$ , $\overline{CE} = V_{IL}$		2 5	4 0	m A
current	Iccı	trc, two =1 $\mu$ s				
		VIN =VIL or VIH, II/0 =OmA, CE =VIL			1 0	m A
Standby	Isв	$\overline{CE} \ge V_{cc} - 0.2V$		0.6	4 0	μΑ
current	Isbi	CE =Vin			3	m A
Output	Vol	Iot= 2.1mA	•		0.4	V
voltage	Vон	I <sub>OH</sub> =-1. OmA	2.4			V

Note) \*4. Typical values at Vcc=5.0V, Ta=25°C.

### 8. AC Electrical Characteristics

### AC Test Conditions

Input pulse level	0.6 V to 2.4 V			
Input rise and fall time	1 0 n s			
Input and Output timing Ref. level	1.5 V			
Output load	1TTL+C <sub>L</sub> (100pF) (*5)			

Note) \*5. Including scope and jig capacitance.

### Read cycle

 $(Ta = -4.0 \, \text{°C} \text{ to } + 8.5 \text{ , } Vcc = 4.5 \, \text{V} \text{ to } 5.5 \, \text{V})$ 

Parameter	Symbol	Min.	Max.	Unit
Read cycle time	t RC	8 5		ns
Address access time	t AA		8 5	ns
CE access time	tace		8 5	ns
Output enable to output valid	toe		3 5	ns
Output hold from address change	tон	1 0		ns
CE Low to output active	tız	1 0		ns
OE Low to output active	tolz	5		ns
CE High to output in High impedance	t H Z	0	3 0	ns
OE High to output in High impedance	tонz	0	3 0	ns

### Write cycle

 $(Ta = -4 \ 0 \ C \ to \ +8 \ 5 \ , Vcc = 4 \ .5 \ V \ to \ 5 \ .5 \ V)$ 

Parameter	Symbol	Min.	Max.	Unit
Write cycle time	t wc	8 5		ns
CE Low to end of write	tcw	5 5		ns
Address valid to end of write	t aw	5 5		ns
Address setup time	t as	0		ns
Write pluse width	twp	4 0		ns
Write recovery time	t wr	0		ns
Input data setup time	t Dw	3 0		ns
Input data hold time	t DH	0		ns
WE High to output active	tow	5		ns
WE Low to output in High impedance	t wz	0	3 0	ns
OE High to output in High impedance	tонz	0	3 0	ns

Note) \*6. Active output to High impedance and High impedance to output active tests specified for a  $\pm 200 \text{mV}$  transition from steady state levels into the test load.

### 9. Data Retention Characteristics

 $(Ta = -4 \ 0 \ C \ to +8 \ 5)$ 

Paramenter	Symbol	Condition	ıs	Min.	Typ. (*7)	Max.	Unit
Data Retention supply voltage	Vccdr	$\overline{CE} \ge V_{CCDR} - 0$ .	2 V	2.0		5.5	V
Data Retention supply current	ICCDR	$V_{CCDR} = 3 V$ $\overline{CE} \ge V_{CCDR} = 0$ .	$T a = 2 5 \mathbb{C}$ $T a = 7 0 \mathbb{C}$ $2 V (*5)$		0.3	1.0 15 20	μ A μ A μ A
Chip enable setup time	tcdr			0			n s
Chip enable hold time	tr			(*8) t rc			n s

Note) ★ 7. Typical values at Ta=25°C

★ 8. Read Cycle

### 10. Pin Capacitance

 $(T_a=25 \text{ °C}, f=1 \text{ MH } z)$ 

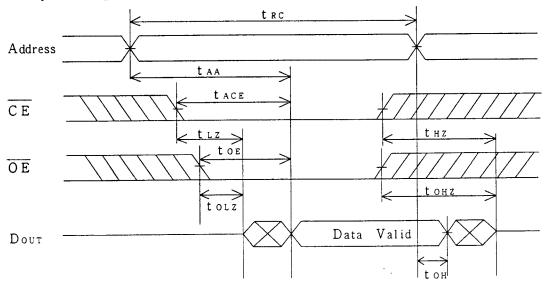
Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit		
Input capacitance	CIN	$V_{IN} = 0 V$			7	p F	<b>*</b> 9	
I/O capacitance	C1/0	$V_{I/O} = 0 \ V$			1 0	рF	<b>*</b> 9	

Note) \*9. This parameter is sampled and not production tested.



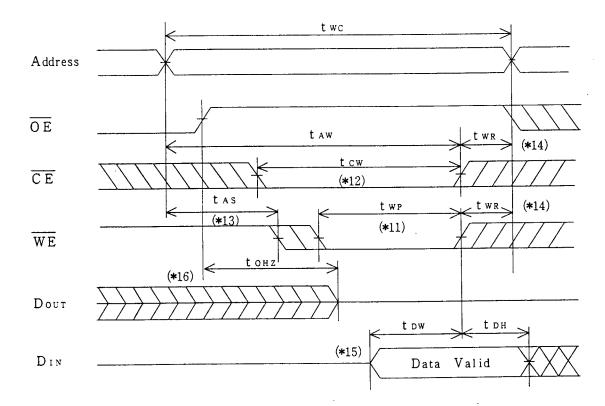
### 11. Timing Chart

Read cycle timing chart - (\*10)

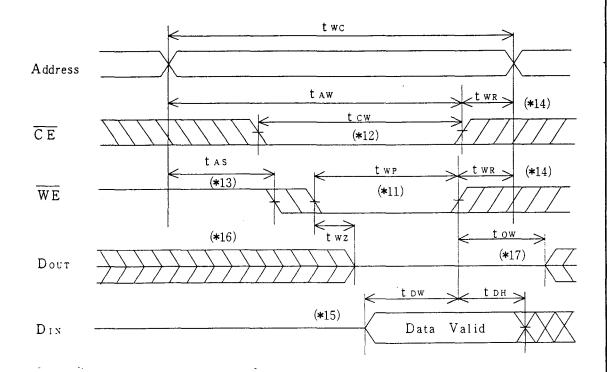


Note) \*10. WE is high for Read cycle.

Write cycle timing chart—  $\overline{\text{(OE)}}$  Controlled)



Write cycle timing chart— (OE Low fixed)



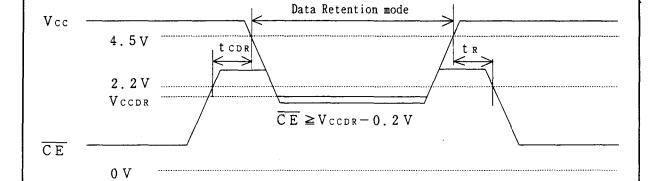
- Note) \* 11. A write occurs during the overlap of a low CE, and a low WE,

  A write begins at the latest transition among CE going low, and WE going low.

  A write ends at the earliest transition among CE going high, and WE going high.

  two is measured from the beginning of write to the end of write.
  - \* 12. tow is measured from the later of  $\overline{CE}$  going low to the end of write.
  - \* 13. tas is measured from the address valid to the beginning of write.
  - \* 14. twn is measured from the end of write to the address change.
  - $\star$  15. During this period, I/O pins are in the output state, therefore the input signals of opposite phase to the outputs must not be applied.
  - \* 16. If  $\overline{\text{CE}}$  goes low simultaneously with  $\overline{\text{WE}}$  going low or after  $\overline{\text{WE}}$  going low, the outputs remain in high impedance state.
  - \* 17. If  $\overline{\text{CE}}$  goes high simultaneously with  $\overline{\text{WE}}$  going high or before  $\overline{\text{WE}}$  going high, the outputs remain in high impedance state.

Data Retention timing chart - (CE Controlled)



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#### 12 Package and packing specification

1. Package Outline Specification
Refer to drawing No. AA 9 3 1

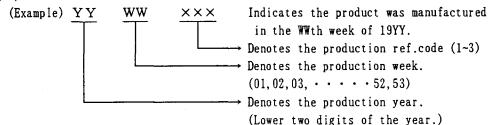
#### 2. Markings

#### 2-1. Marking contents

(1) Product name : LH52256CHN-85LL

(2) Company name: SHARP

(3) Date code



(4) The marking of "JAPAN" indicates the country of origin.

#### 2-2. Marking layout

Refer to drawing No. AA931

(This layout do not define the dimensions of marking character and marking position.)

3. Packing Specification (Dry packing for surface mount packages)

Dry packing is used for the purpose of maintaining IC quality after mounting packages on the PCB (Printed Circuit Board).

When the epoxy resin which is used for plastic packages is stored at high humidity, it may absorb 0.15% or more of its weight in moisture. If the surface mount type package for a relatively large chip absorbs a large amount of moisture between the epoxy resin and insert material (e.g. chip, lead frame) this moisture may suddenly vaporize into steam when the entire package is heated during the soldering process (e.g. VPS). This causes expansion and results in separation between the resin and insert material, and sometimes cracking of the package. This dry packing is designed to prevent the above problem from occurring in surface mount packages.

3-1. Packing Materials

Material Name	Material Specification	Purpose		
Magazine	Anti-static treated plastic	Packing of device		
	(25devices/magazine)			
Stopper	Plastic or rubber	Fixing of device		
Cap	Plastic (2caps/bag)	Fixing of Magazine		
Laminated aluminum	Aluminum polyethylene	Drying of device		
bag	(lbag/case)			
Desiccant	Silica gel	Drying of device		
Inner case	Card board (1000devices/case)	Packaging of device		
Label	Paper	Indicates part number, quantity		
		and date of manufacture		
Outer case	Card board	Outer packing of Magazine		

(Devices shall be inserted into a magazine (sleeve) in the same direction.)

- 3-2. Outline dimension of magazine (sleeve) Refer to attached drawing
- 4. Storage and Opening of Dry Packing
  - 4-1. Store under conditions shown below before opening the dry packing

(1) Temperature range : 5~40°C

(2) Humidity : 80% RH or less

- 4-2. Notes on opening the dry packing
  - (1) Before opening the dry packing, prepare a working table which is grounded against ESD and use a grounding strap.
  - (2) The magazine has been treated to be conductive or anti-static. If the device is transferred to another magazine, use a equivalent magazine.
  - (3) A stopper is included with the magazine. Before storage, make sure the stopper is inserted.
- 4-3. Storage after opening the dry packing

Perform the following to prevent absorption of moisture after opening.

- (1) After opening the dry packing, store the ICs in an environment with a temperature of  $5\sim25^{\circ}$ C and a relative humidity of 60% or less and mount ICs within 4 days after opening dry packing.
- (2) To re-store the ICs for an extended period of time within 4 days after opening the dry packing, use a dry box or re-seal the ICs in the dry packing with desiccant (whoes indicater is blue), and store in an environment with a temperature of  $5\sim40^{\circ}$ C and a relative humidity of 80% or less, and mount ICs within 2 weeks.
- (3) Total period of storage after first opening and re-opening is within 4 days, and store the ICs in the same environment as section 4-3.(1).

First opening  $\longrightarrow$   $X_1 \longrightarrow$  re-sealing  $\longrightarrow$   $Y \longrightarrow$  re-opening  $\longrightarrow$   $X_2 \longrightarrow$  mounting

ICs in dry  $5 \sim 25 ^{\circ} C$   $5 \sim 40 ^{\circ} C$   $5 \sim 25 ^{\circ} C$ packing 60 % RH or less 80 % RH or less 60 % RH or less

 $X_1 + X_2$ : within 4 days Y: within 2 weeks

- 4-4. Baking (drying) before mounting
  - (1) Baking is necessary
    - (A) If the humidity indicator in the desiccant becomes pink
    - (B) If the procedure in section 4-3 could not be performed
  - (2) Recommended baking conditions If the above conditions (A) and (B) are applicable, bake it before mounting. The recommended conditions are 16~24 hours at 120℃ or 5~10 hours at 150℃. Note that the standard magazine can not be baked. Use the heat resistant magazine.
  - (3) Storage after baking
    After baking ICs, store the ICs in the same environment as section
    4-3.(1).

5. Surface Mount Conditions

Please perform the following conditions when mounting ICs not to deteriorate IC quality.

5-1 . Soldering conditions (The following conditions are valid only for one time soldering.)

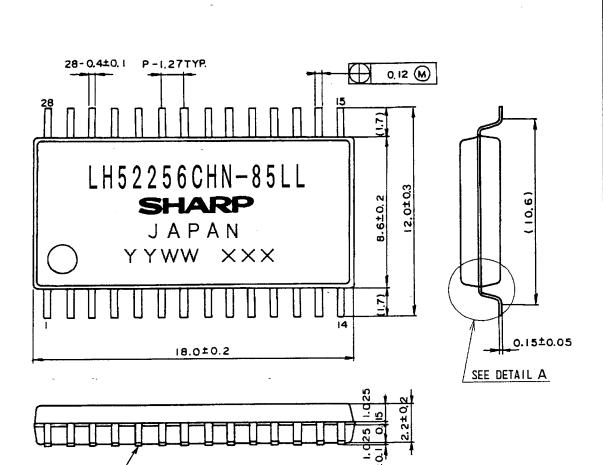
Mounting Method	Temperature and Duration	Measurement Point	
Reflow soldering	Peak temperature of 240°C,	IC surface	
(air)	duration less than 15 seconds		
	above 230℃, temperature		
	increase rate of $1\sim4$ °C/second		
Solder dipping	245℃ or less, duration less	Solder bath	
	than 3 seconds/dip, total of		
	5 seconds		
Vapor phase	215℃ or less, duration less	Steam	
solderring	than 40 seconds above 200℃		
Manual soldering	260℃ or less, duration less	IC outer lead surface	
(soldering iron)	than 10 seconds		

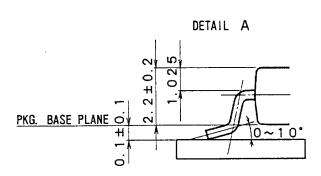
5-2. Conditions for removal of residual flux

(1) Ultrasonic washing power(2) Washing time25 Watts/liter or lessTotal 1 minute maximum

(3) Solvent temperature : 15~40°C





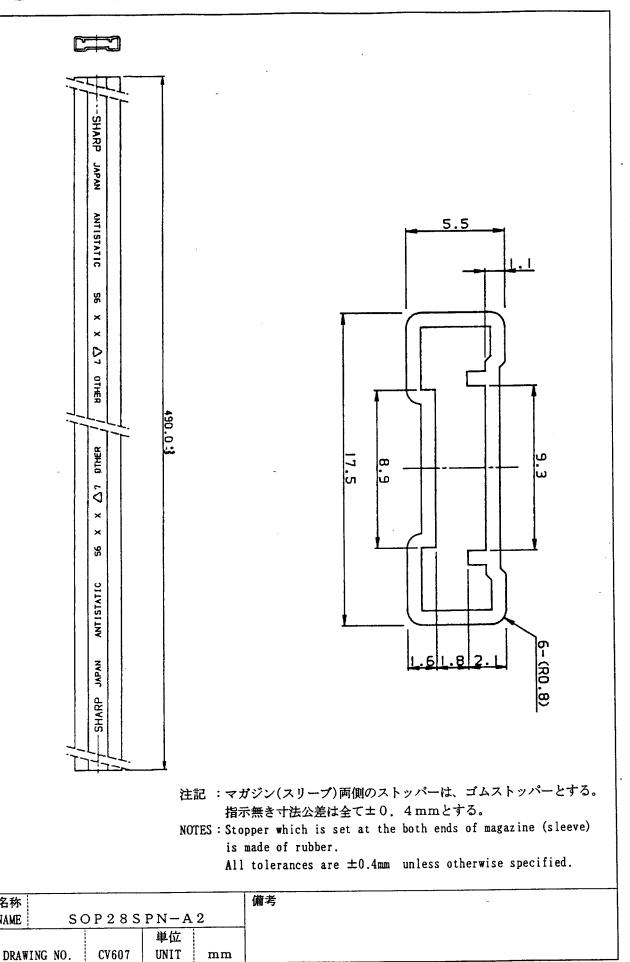


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名称		リード仕上		TIN-LEAD	備考	ブラスチックパッケージ外形寸法は、パリを含まないものとする。	
NAME	SOP28-P	<b>-4</b> 50	LEAD	FINISH	PLATING	NOTE	Plastic body dimensions do not include burr
		!		単位	!		of resin.
DRAWI	ING NO.	AA93	1	UNIT	mm		

名称

NAME



STATIC SRAM RAM Random Access Memory Low Power SOP Industrial Temp LH52256CHN-85LL 256K (32K x 8)